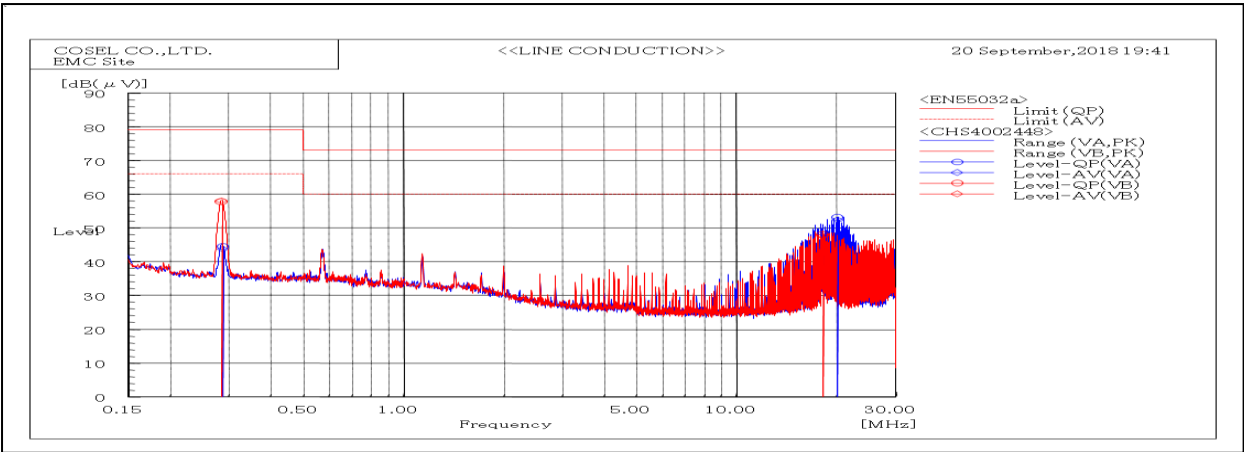
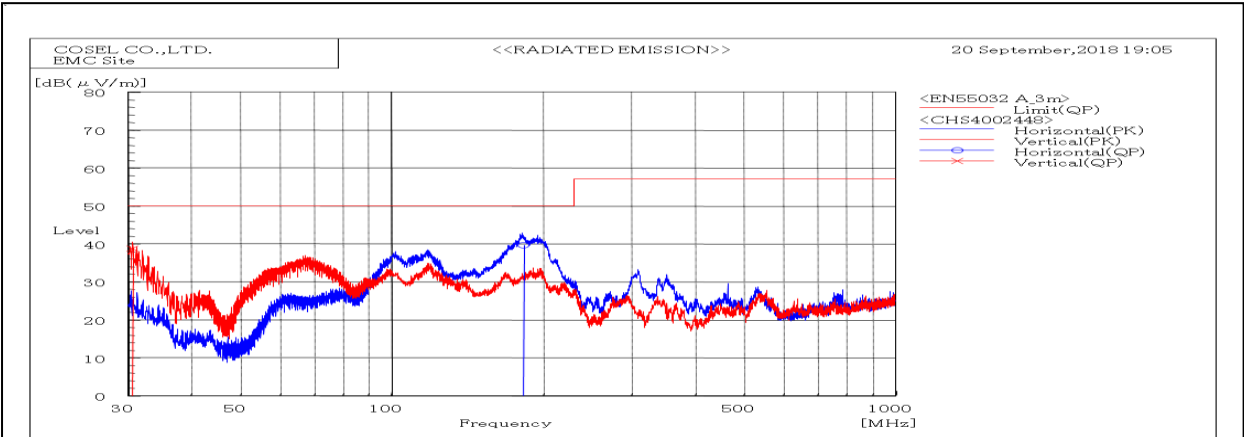


DATA SHEET		Date	27-Sep-18
Model	CHS4002448	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Nakagawa



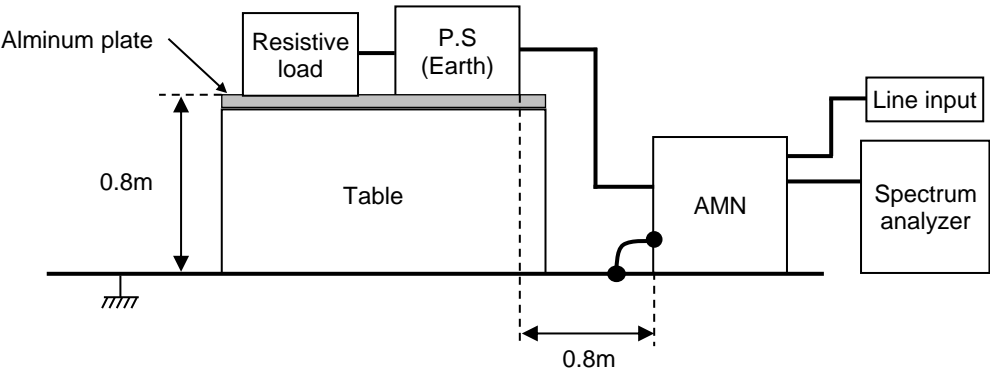
Frequency MHz	Line Phase	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.28489	VB	57.8	58.1	79	66	21.2	7.9	Pass	
0.28821	VA	44.5	43.7	79	66	34.5	22.3	Pass	
18.16205	VB	48.1	47.5	73	60	24.9	12.5	Pass	
20.153	VA	53.1	52.4	73	60	19.9	7.6	Pass	



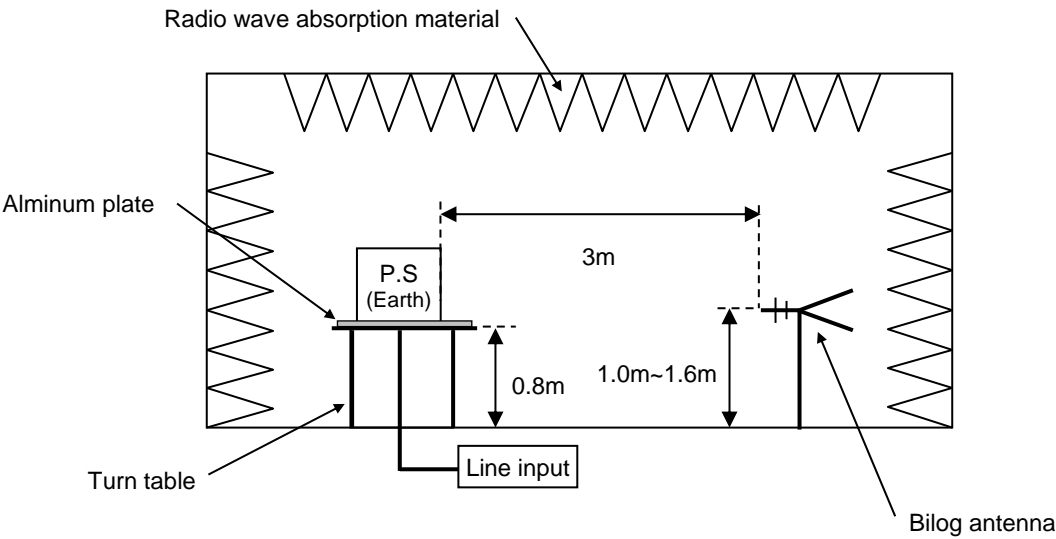
Frequency MHz	Polarization	Stability	Reading dB(uV)	Limit dB(uV/m)	Margin dB(uV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
30.590	V	Stable	38.7	50.0	11.3	Pass	101	114	
182.701	H	Stable	39.6	50.0	10.4	Pass	141	336	

DATA SHEET		Date	27-Sep-18
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Nakagawa

1. Line conduction



2. Radiated emission

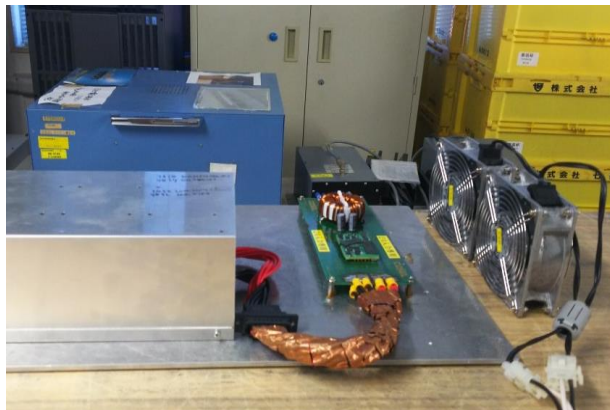


Conditions

Test : EMI
Model Name : CHS40024□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

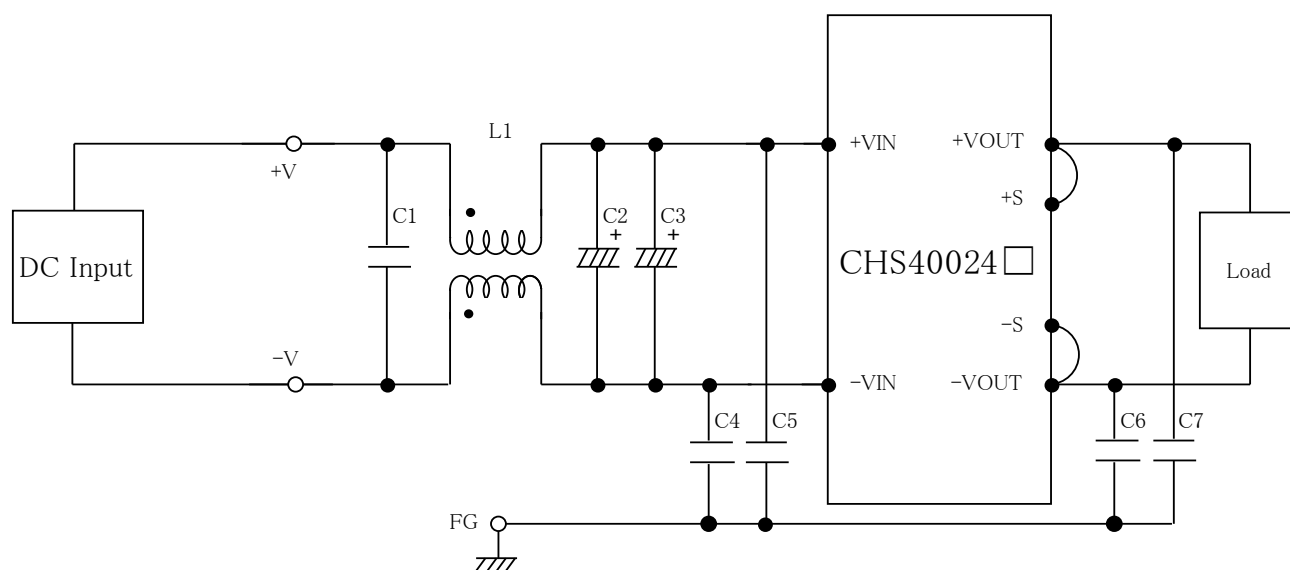


Fig.1 Testing circuitry

L1 : 1mH SC-30-100 (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2,C3 : 50V 330 μ F PWseries (nichicon)
C4,C5 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C6,C7 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)